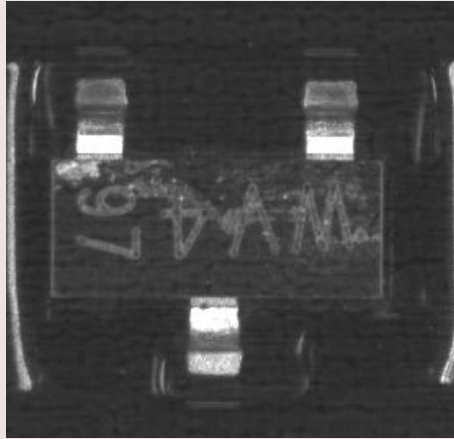


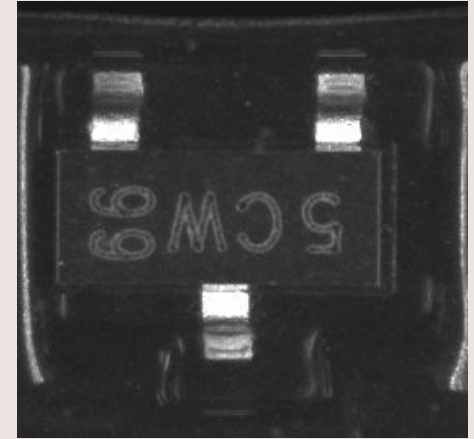
Nexperia Image Classification Using CNN

1. Overview



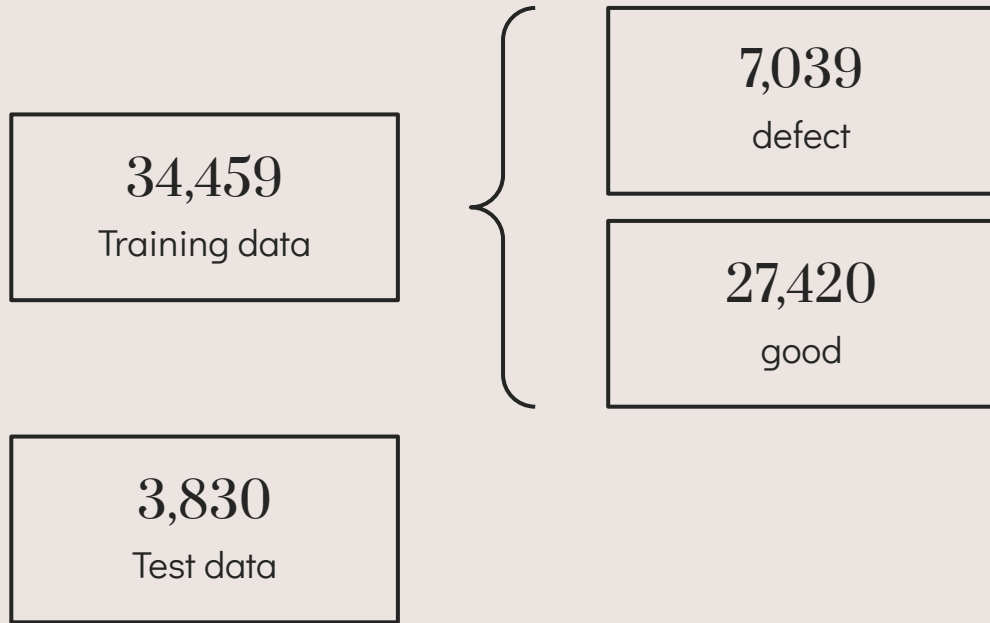
defect

Help Nexperia pick
defect devices from a
batch of
semiconductors

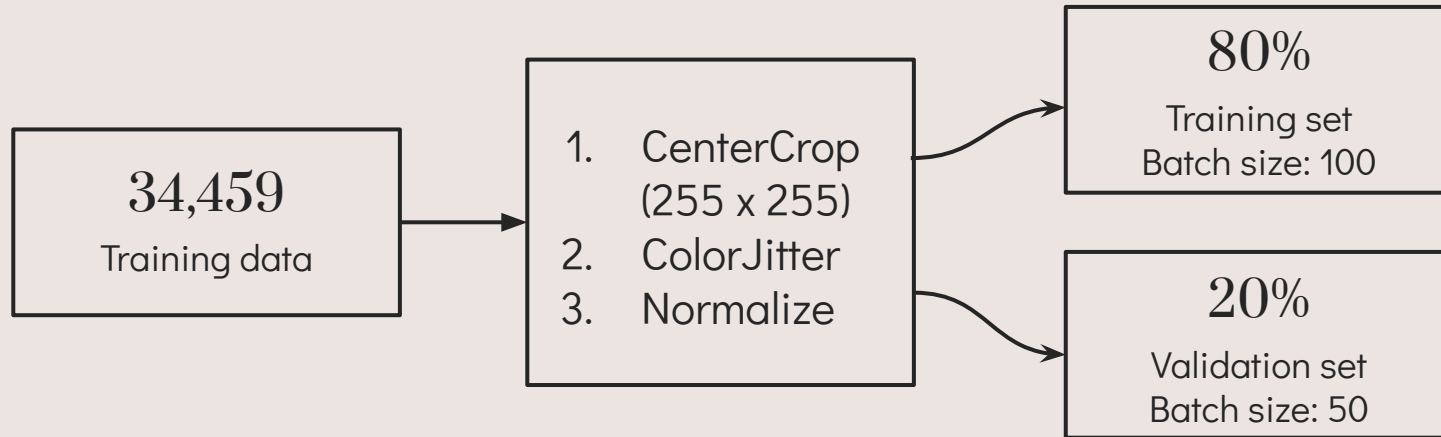


good

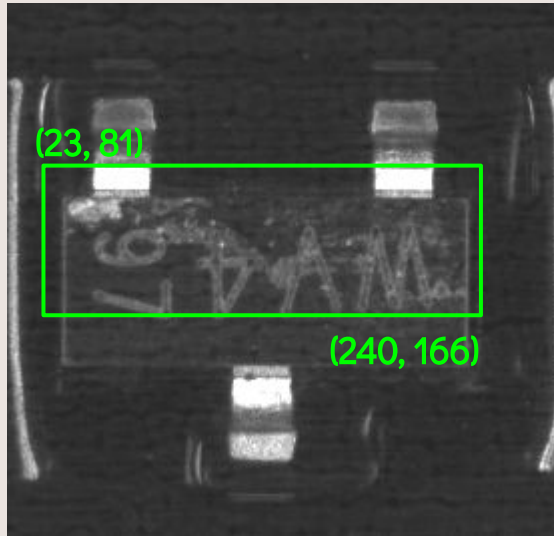
2. Data Preprocessing



2. Data Preprocessing

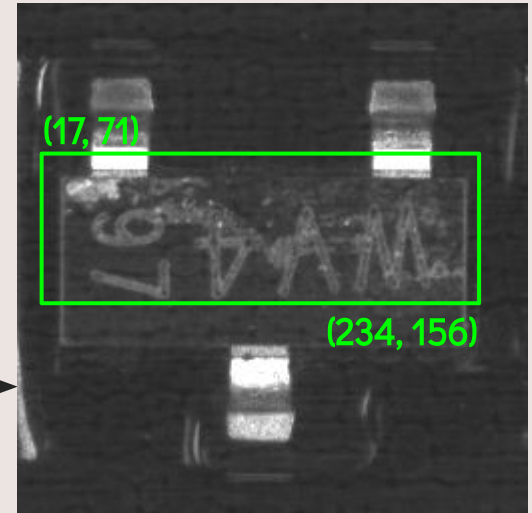


2. Data Preprocessing

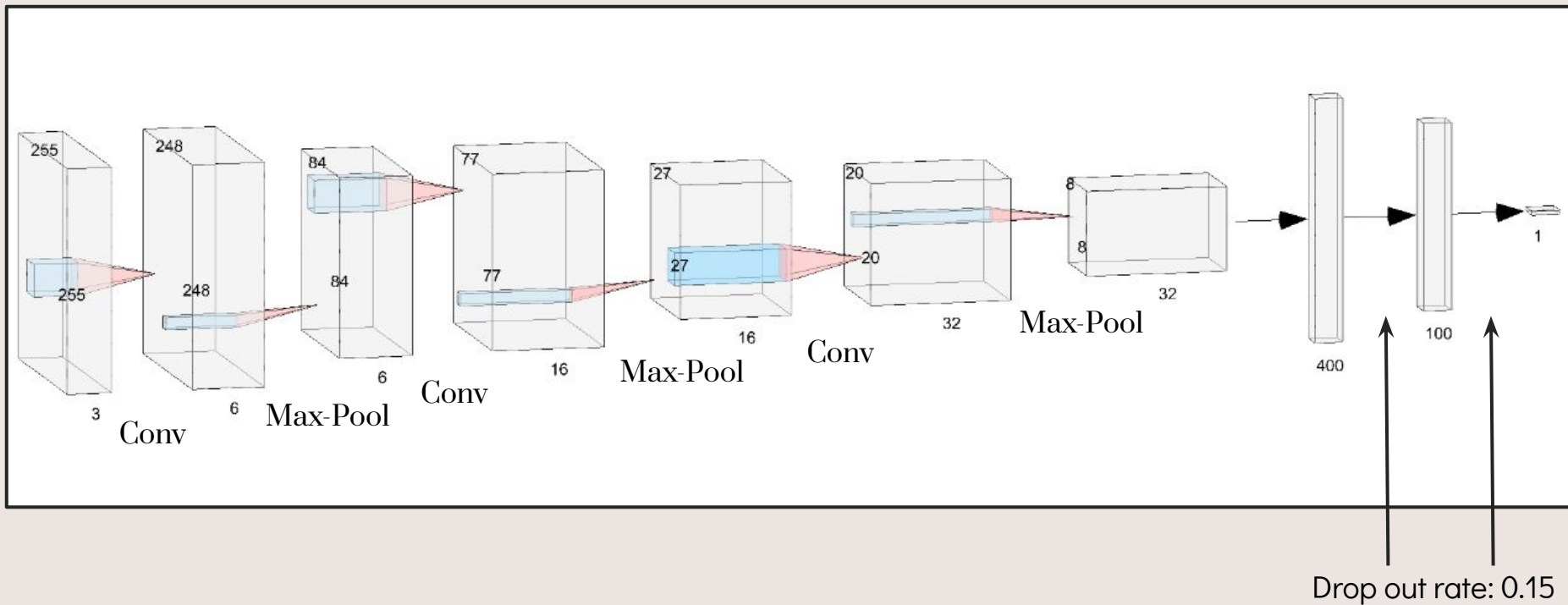


defect_area.csv

1. Match the coordinates after cropping
2. Fill in missing values

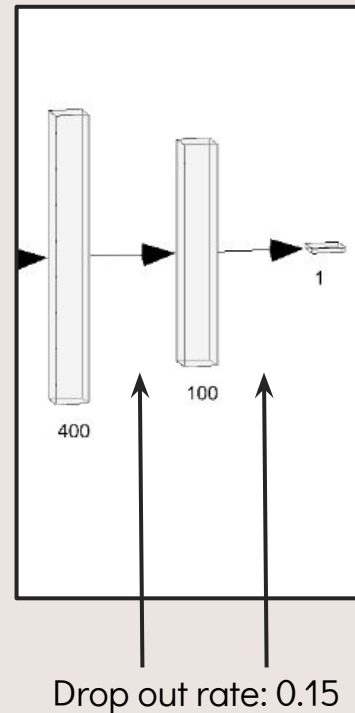


3. Model



4. Hyperparameter tuning

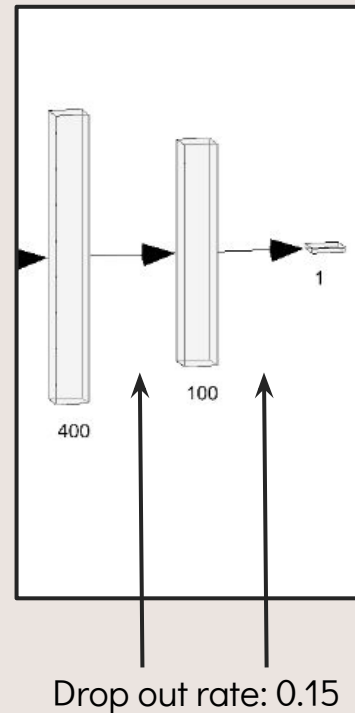
- Average training loss of the last 10 training batches
- Dropout rate (Initial: 0.3)
 - 0.1 0.216
 - **0.15 0.213**
 - 0.2 0.232
 - 0.25 0.243
 - 0.3 0.289
 - 0.35 0.332
 - 0.4 0.341
 - 0.45 0.386



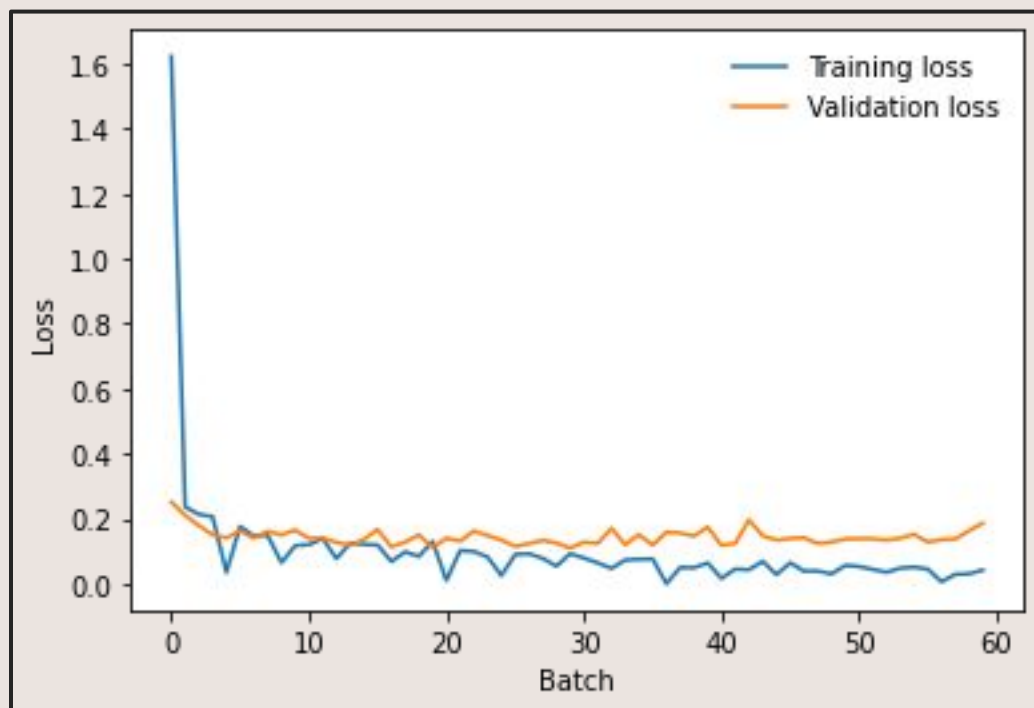
4. Hyperparameter tuning

- Number of nodes in dense layer (Initial: 1000-200)

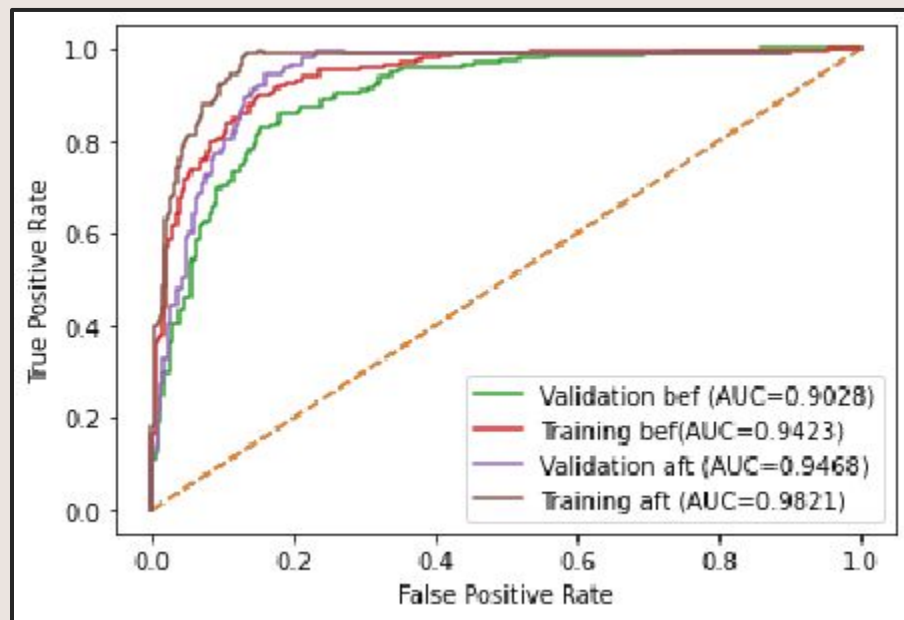
○ 1500-1000 0.122	○ 600-500 0.116
○ 1500-500 0.099	○ 600-100 0.048
○ 1500-100 0.071	○ 600-50 0.092
○ 1500-50 0.202	○ 600-10 0.213
○ 1500-10 0.327	○ 400-100 0.043
○ 1000-500 0.109	○ 400-50 0.095
○ 1000-100 0.051	○ 400-10 0.301
○ 1000-50 0.181	○ 200-100 0.102
○ 1000-10 0.229	○ 200-50 0.128
	○ 200-10 0.305



5. Result



5. Result



5. Result

Before tuning

Accuracy: 0.9070	label: defect	label: good
predict: defect	1126 (0.1634)	359 (0.0521)
predict: good	282 (0.0409)	5125 (0.7436)
Precision: 0.7582	Recall: 0.7997	F1 Score: 0.7783

Dropout rate: 0.15

Accuracy: 0.9571	label: defect	label: good
predict: defect	1233 (0.1790)	121 (0.0176)
predict: good	175 (0.0254)	5363 (0.7782)
Precision: 0.9106	Recall: 0.8757	F1 Score: 0.8928

Fully Connected layers: 400-100

Accuracy: 0.9830	label: defect	label: good
predict: defect	1373 (0.1993)	82 (0.0119)
predict: good	35 (0.0051)	5402 (0.7839)
Precision: 0.9436	Recall: 0.9751	F1 Score: 0.9591

6. Conclusion

Kaggle AUC Score: 0.97822

The result is much better after the hyperparameter tuning.

Not as good as transfer learning result (from other students).